

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/535,644	<b>Applicant(s)/Patent under Reexamination</b> KIM, YOUNG-HOON
<b>Examiner</b> Devon C. Kramer	<b>Art Unit</b> 3683	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
<i>east</i>		<i>5/16/07</i>	<i>JR</i>